

## PowerMOS transistor

BUK482-100A

## GENERAL DESCRIPTION

N-channel enhancement mode field-effect power transistor in a plastic envelope suitable for surface mount applications.  
The device is intended for use in automotive and general purpose switching applications.

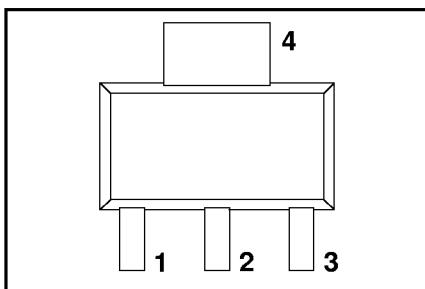
## QUICK REFERENCE DATA

SYMBOL	PARAMETER	MAX.	UNIT
$V_{DS}$	Drain-source voltage	100	V
$I_D$	Drain current (DC)	1.8	A
$P_{tot}$	Total power dissipation	1.8	W
$T_J$	Junction temperature	150	°C
$R_{DS(ON)}$	Drain-source on-state resistance; $V_{GS} = 10$ V	0.28	Ω

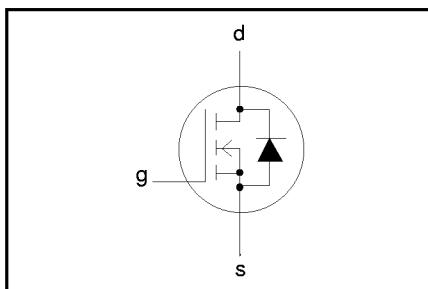
## PINNING - SOT223

PIN	DESCRIPTION
1	gate
2	drain
3	source
4	drain (tab)

## PIN CONFIGURATION



## SYMBOL



## LIMITING VALUES

Limiting values in accordance with the Absolute Maximum System (IEC 134)

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
$V_{DS}$	Drain-source voltage	-	-	100	V
$V_{DGR}$	Drain-gate voltage	$R_{GS} = 20$ kΩ	-	100	V
$\pm V_{GS}$	Gate-source voltage	-	-	30	V
$I_D$	Drain current (DC)	$T_{amb} = 25$ °C	-	1.8	A
$I_D$	Drain current (DC)	$T_{amb} = 100$ °C	-	1.1	A
$I_{DM}$	Drain current (pulse peak value)	$T_{amb} = 25$ °C	-	7.2	A
$P_{tot}$	Total power dissipation	$T_{amb} = 25$ °C	-	1.8	W
$T_{stg}$	Storage temperature	-	-55	150	°C
$T_j$	Junction Temperature	-	-	150	°C

## THERMAL RESISTANCES

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
$R_{th j-b}$	From junction to board <sup>1</sup>	Mounted on any PCB	-	40	-	K/W
$R_{th j-amb}$	From junction to ambient	Mounted on PCB of Fig.17	-	-	70	K/W

<sup>1</sup> Temperature measured 1-3 mm from tab.

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**STATIC CHARACTERISTICS** $T_j = 25^\circ\text{C}$  unless otherwise specified

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
$V_{(\text{BR})\text{DSS}}$	Drain-source breakdown voltage	$V_{GS} = 0 \text{ V}; I_D = 0.25 \text{ mA}$	100	-	-	V
$V_{GS(\text{TO})}$	Gate threshold voltage	$V_{DS} = V_{GS}; I_D = 1 \text{ mA}$	2.1	3.0	4.0	V
$I_{DSS}$	Zero gate voltage drain current	$V_{DS} = 100 \text{ V}; V_{GS} = 0 \text{ V}$	-	1	10	$\mu\text{A}$
$I_{GSS}$	Zero gate voltage drain current	$V_{DS} = 100 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 125^\circ\text{C}$	-	0.1	1.0	mA
$R_{DS(\text{ON})}$	Gate source leakage current	$V_{GS} = \pm 30 \text{ V}; V_{DS} = 0 \text{ V}$	-	10	100	nA
	Drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 1.8 \text{ A}$	-	0.21	0.28	$\Omega$

**DYNAMIC CHARACTERISTICS** $T_j = 25^\circ\text{C}$  unless otherwise specified

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
$g_{fs}$	Forward transconductance	$V_{DS} = 25 \text{ V}; I_D = 1.8 \text{ A}$	1.5	2.5	-	S
$C_{iss}$	Input capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = 25 \text{ V}; f = 1 \text{ MHz}$	-	300	500	pF
$C_{oss}$	Output capacitance		-	90	120	pF
$C_{rss}$	Feedback capacitance		-	35	50	pF
$t_{d\text{ on}}$	Turn-on delay time	$V_{DD} = 30 \text{ V}; I_D = 3 \text{ A}$	-	9	14	ns
$t_r$	Turn-on rise time	$V_{GS} = 10 \text{ V}; R_{GS} = 50 \Omega$	-	25	40	ns
$t_{d\text{ off}}$	Turn-off delay time	$R_{gen} = 50 \Omega$	-	30	45	ns
$t_f$	Turn-off fall time		-	20	40	ns

**REVERSE DIODE LIMITING VALUES AND CHARACTERISTICS** $T_j = 25^\circ\text{C}$  unless otherwise specified

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
$I_{DR}$	Continuous reverse drain current	-	-	-	1.8	A
$I_{DRM}$	Pulsed reverse drain current	-	-	-	7.2	A
$V_{SD}$	Diode forward voltage	$I_F = 1.8 \text{ A}; V_{GS} = 0 \text{ V}$	-	0.85	1.1	V

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
$t_{rr}$	Reverse recovery time	$I_F = 1.8 \text{ A}; -dI_F/dt = 100 \text{ A}/\mu\text{s}$	-	80	-	ns
$Q_{rr}$	Reverse recovery charge	$V_{GS} = -10 \text{ V}; V_R = 30 \text{ V}$	-	0.30	-	$\mu\text{C}$

**AVALANCHE LIMITING VALUE**

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
$W_{DSS}$	Drain-source non-repetitive unclamped inductive turn-off energy	$I_D = 1.8 \text{ A}; V_{DD} \leq 25 \text{ V}; V_{GS} = 10 \text{ V}; R_{GS} = 50 \Omega; T_{amb} = 25^\circ\text{C}$	-	-	40	mJ

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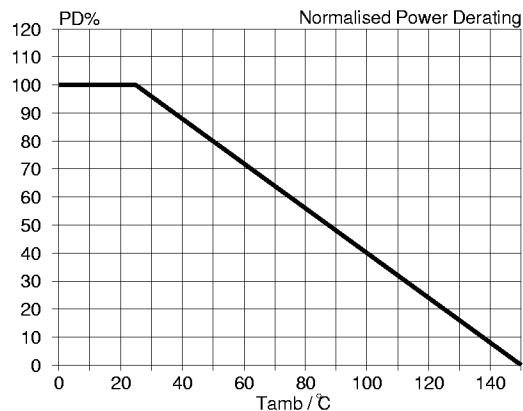


Fig.1. Normalised power dissipation.  
 $PD\% = 100 \cdot P_D / P_{D\ 25\ ^\circ C} = f(T_{amb})$

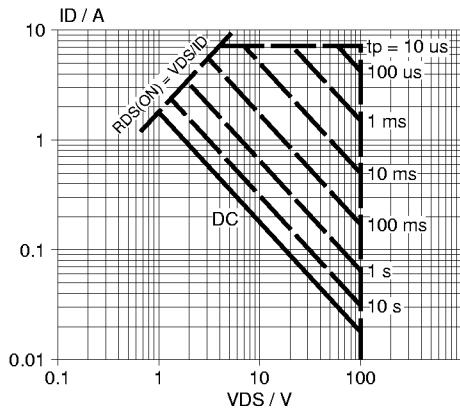


Fig.4. Safe operating area.  $T_{amb} = 25\ ^\circ C$ .  
 $I_D$  &  $I_{DM}$  =  $f(V_{DS})$ ;  $I_{DM}$  single pulse; parameter  $t_p$

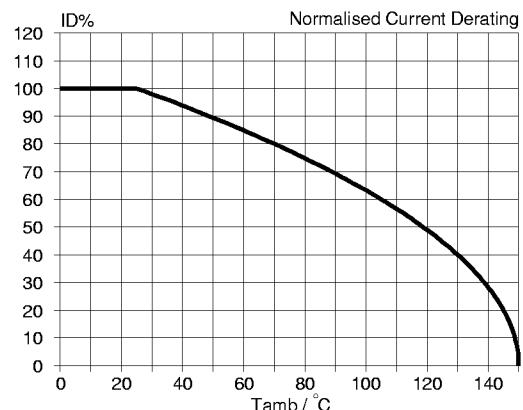


Fig.2. Normalised continuous drain current.  
 $ID\% = 100 \cdot I_D / I_{D\ 25\ ^\circ C} = f(T_{amb})$ ; conditions:  $V_{GS} \geq 10\ V$

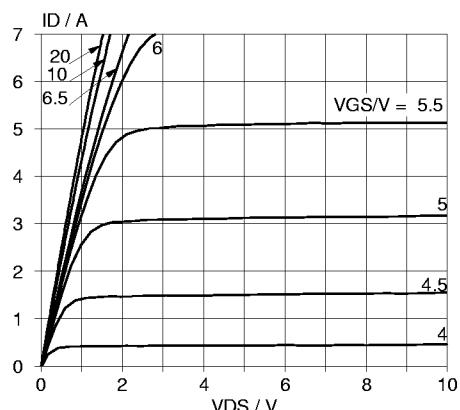


Fig.5. Typical output characteristics,  $T_j = 25\ ^\circ C$ .  
 $I_D = f(V_{DS})$ ; parameter  $V_{GS}$

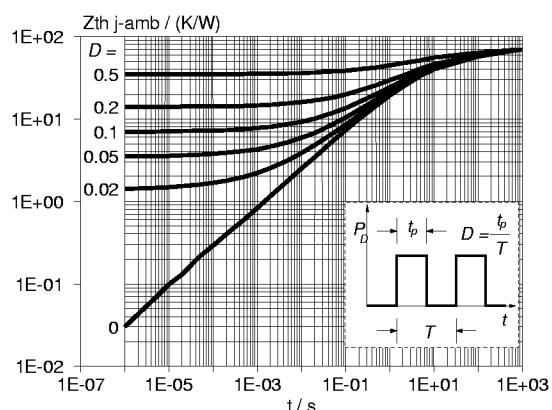


Fig.3. Transient thermal impedance.  
 $Z_{th\ j-amb} = f(t)$ ; parameter  $D = t_p/T$

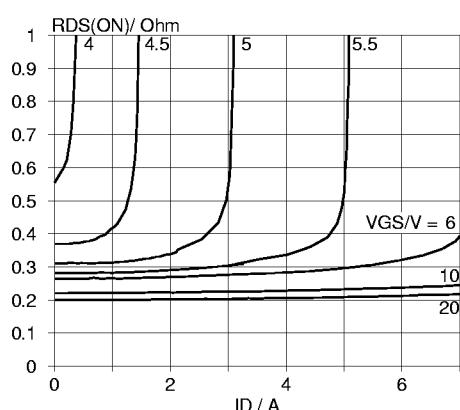


Fig.6. Typical on-state resistance,  $T_j = 25\ ^\circ C$ .  
 $R_{DS(ON)} = f(I_D)$ ; parameter  $V_{GS}$

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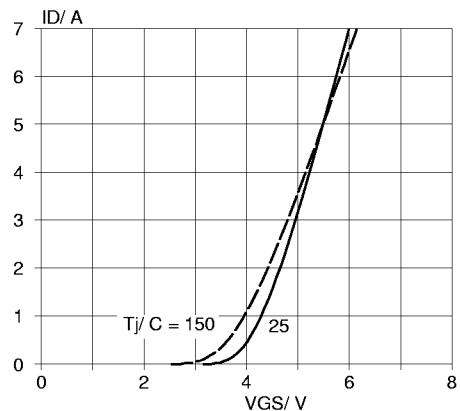


Fig.7. Typical transfer characteristics.  
 $I_D = f(V_{GS})$ ; conditions:  $V_{DS} = 25$  V; parameter  $T_j$

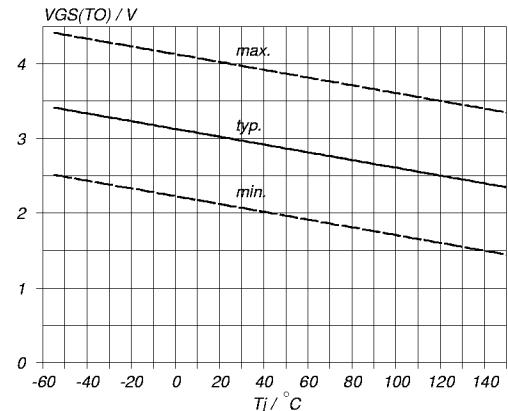


Fig.10. Gate threshold voltage.  
 $V_{GTO} = f(T_j)$ ; conditions:  $I_D = 1$  mA;  $V_{DS} = V_{GS}$

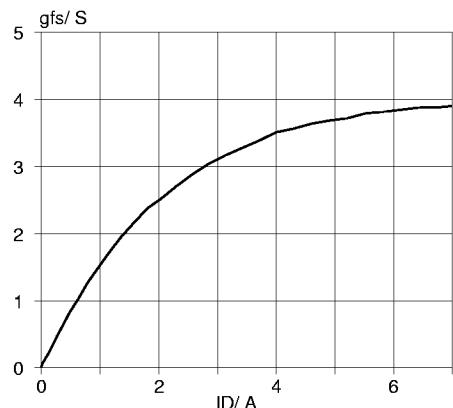


Fig.8. Typical transconductance,  $T_j = 25$  °C.  
 $g_{fs} = f(I_D)$ ; conditions:  $V_{DS} = 25$  V

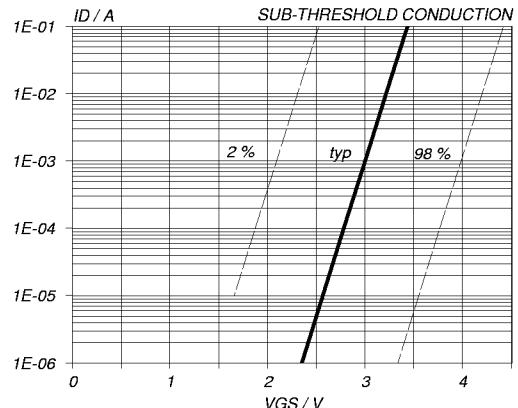


Fig.11. Sub-threshold drain current.  
 $I_D = f(V_{GS})$ ; conditions:  $T_j = 25$  °C;  $V_{DS} = V_{GS}$

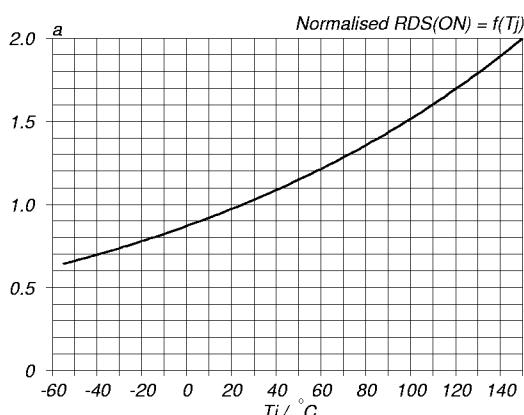


Fig.9. Normalised drain-source on-state resistance.  
 $a = R_{DSON}/R_{DSON25\text{ }^{\circ}\text{C}} = f(T_j)$ ;  $I_D = 1.8$  A;  $V_{GS} = 10$  V

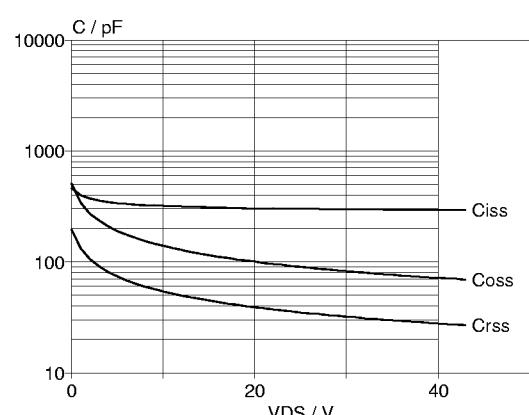


Fig.12. Typical capacitances,  $C_{iss}$ ,  $C_{oss}$ ,  $C_{rss}$ .  
 $C = f(V_{DS})$ ; conditions:  $V_{GS} = 0$  V;  $f = 1$  MHz

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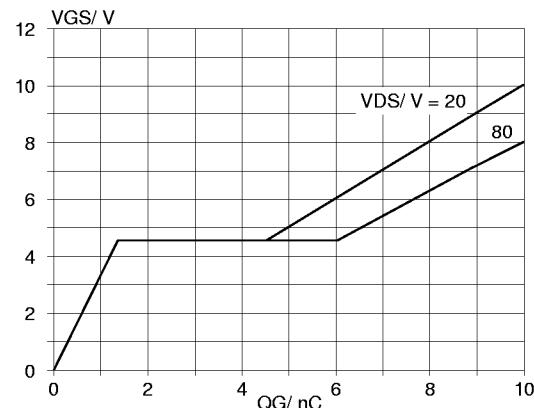


Fig.13. Typical turn-on gate-charge characteristics.  
 $V_{GS} = f(Q_G)$ ; conditions:  $I_D = 1.8 \text{ A}$ ; parameter  $V_{DS}$

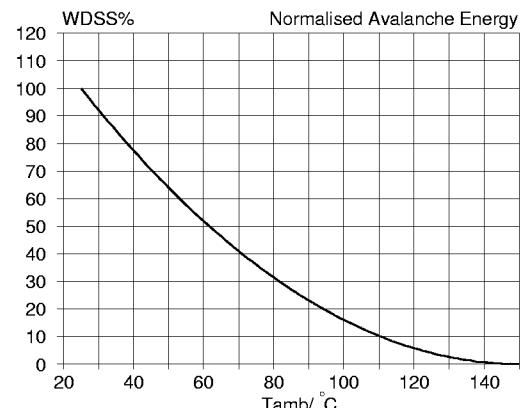


Fig.15. Normalised avalanche energy rating.  
 $W_{DSS\%} = f(T_{amb})$ ; conditions:  $I_D = 1.8 \text{ A}$

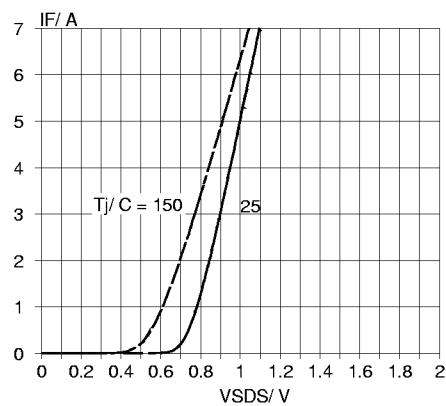


Fig.14. Typical reverse diode current.  
 $I_F = f(V_{SDS})$ ; conditions:  $V_{GS} = 0 \text{ V}$ ; parameter  $T_j$

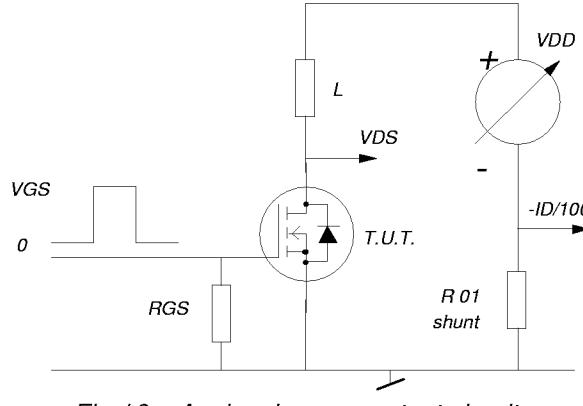


Fig.16. Avalanche energy test circuit.  
 $W_{DSS} = 0.5 \cdot L I_D^2 \cdot BV_{DSS} / (BV_{DSS} - V_{DD})$

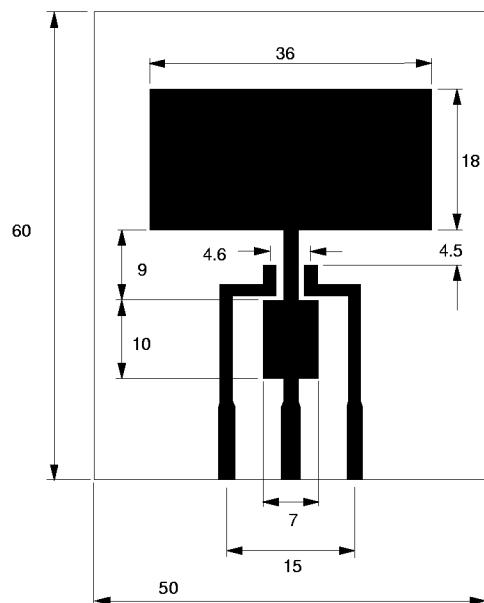
**PRINTED CIRCUIT BOARD***Dimensions in mm.*

Fig.17. PCB for thermal resistance and power rating for SOT223.  
PCB: FR4 epoxy glass (1.6 mm thick), copper laminate (35  $\mu\text{m}$  thick).

**MECHANICAL DATA***Dimensions in mm*

Net Mass: 0.11 g

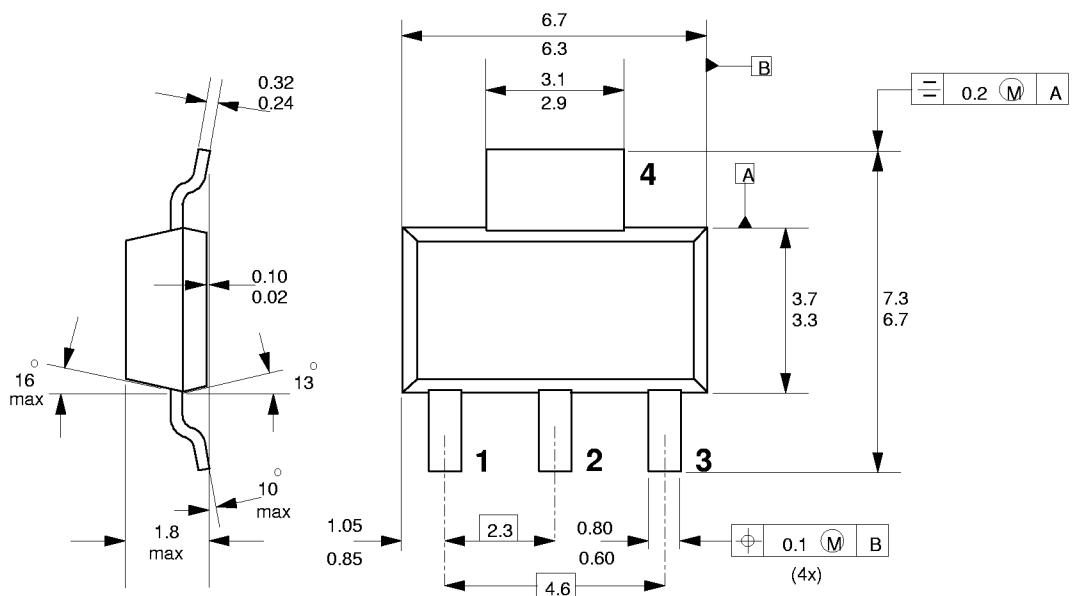


Fig.18. SOT223 surface mounting package.

**Notes**

1. Observe the general handling precautions for electrostatic-discharge sensitive devices (ESDs) to prevent damage to MOS gate oxide.
2. Refer to surface mounting instructions for SOT223 envelope.
3. Epoxy meets UL94 V0 at 1/8".